

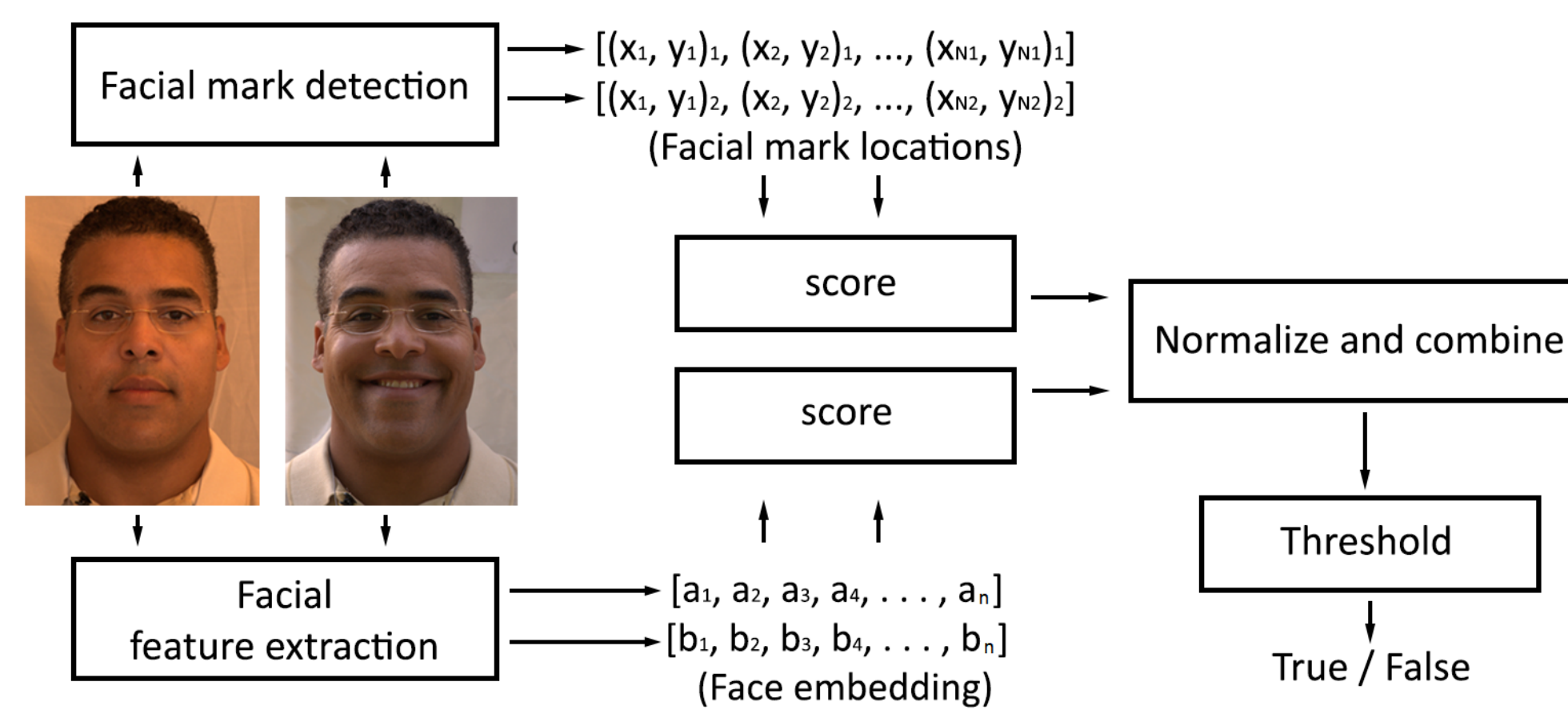
# FACIAL MARKS: DETECTION AND FUSION WITH FRS

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## Introduction

- Facial marks include moles, scars and freckles and can potentially be highly discriminating [Sr12].
- This work studies recognition, detection and biometric performance of facial marks for recognition, standalone and combined with face recognition system (FRS).
- Facial mark recognition (FMR): whether a skin patch from a facial image contains a facial mark. Facial mark detection (FMD): localization facial marks within a face using FMR.



## Research questions

- RQ1: FMR: influence factors on performance?
- RQ2: FMD: use sliding window or deep learning?
- RQ3: Face recognition performance using only facial marks?
- RQ4: Face recognition performance using fusion facial marks and FRS?

## Experimental setup

- Datasets: FRGC non-twins (manually annotated facial mark location in [ZVS17] based on [FR]), set of twins [Ph11]: (non-mated comparisons within twins and between twins: Twins), and another set of twins (non-mated comparisons only between twins: Twins Diff).
- Two FMD methods: iterative sliding window and EfficientDet [TPL]. Trained on FRGC, evaluation on all datasets.

## Experimental setup

- Two (overlap ( $p$  is number of overlapping points,  $N = N_1 + N_2$  total number of facial marks) and point cloud ( $\mathbf{p}_{i,j} \in P_j$  averaged negative distance between point clouds)) score functions.

$$s_o(P_1, P_2) = \begin{cases} 1 & \text{for } N = 0 \\ \frac{2p}{N} & \text{for } N > 0 \end{cases}, \quad (1)$$

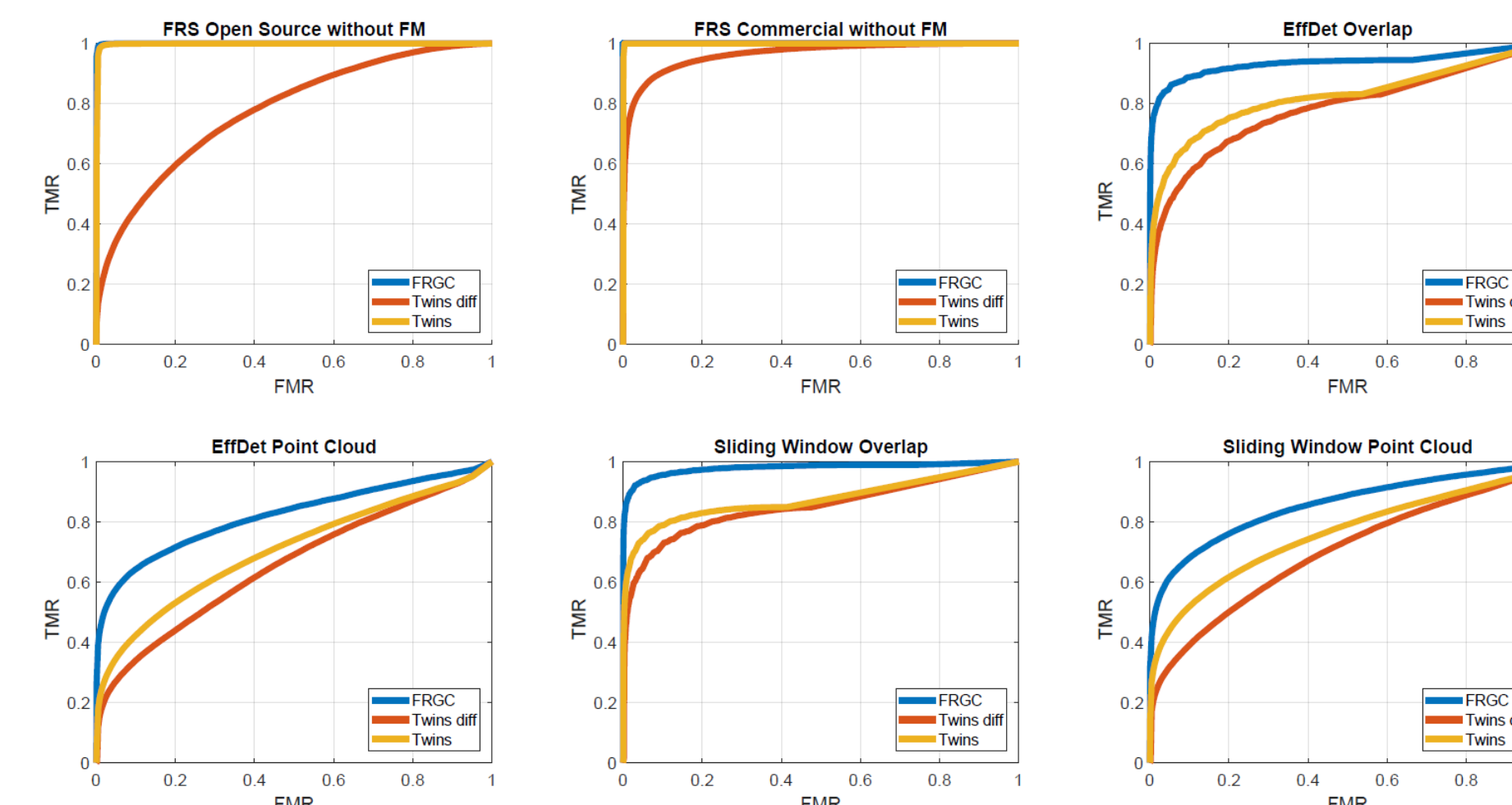
$$s_{pc}(P_1, P_2) = -\frac{1}{N_1} \sum_{i=1}^{N_1} d(\mathbf{p}_{i,1}, P_2) - \frac{1}{N_2} \sum_{i=1}^{N_2} d(\mathbf{p}_{i,2}, P_1). \quad (2)$$

- Adaptive z-score normalization and fusion:

$$Z = \frac{S - \hat{\mu}}{\hat{\sigma}}, \quad S_{c,\alpha} = Z_{FMD} \pm \alpha \cdot Z_{FRS} \quad (3)$$

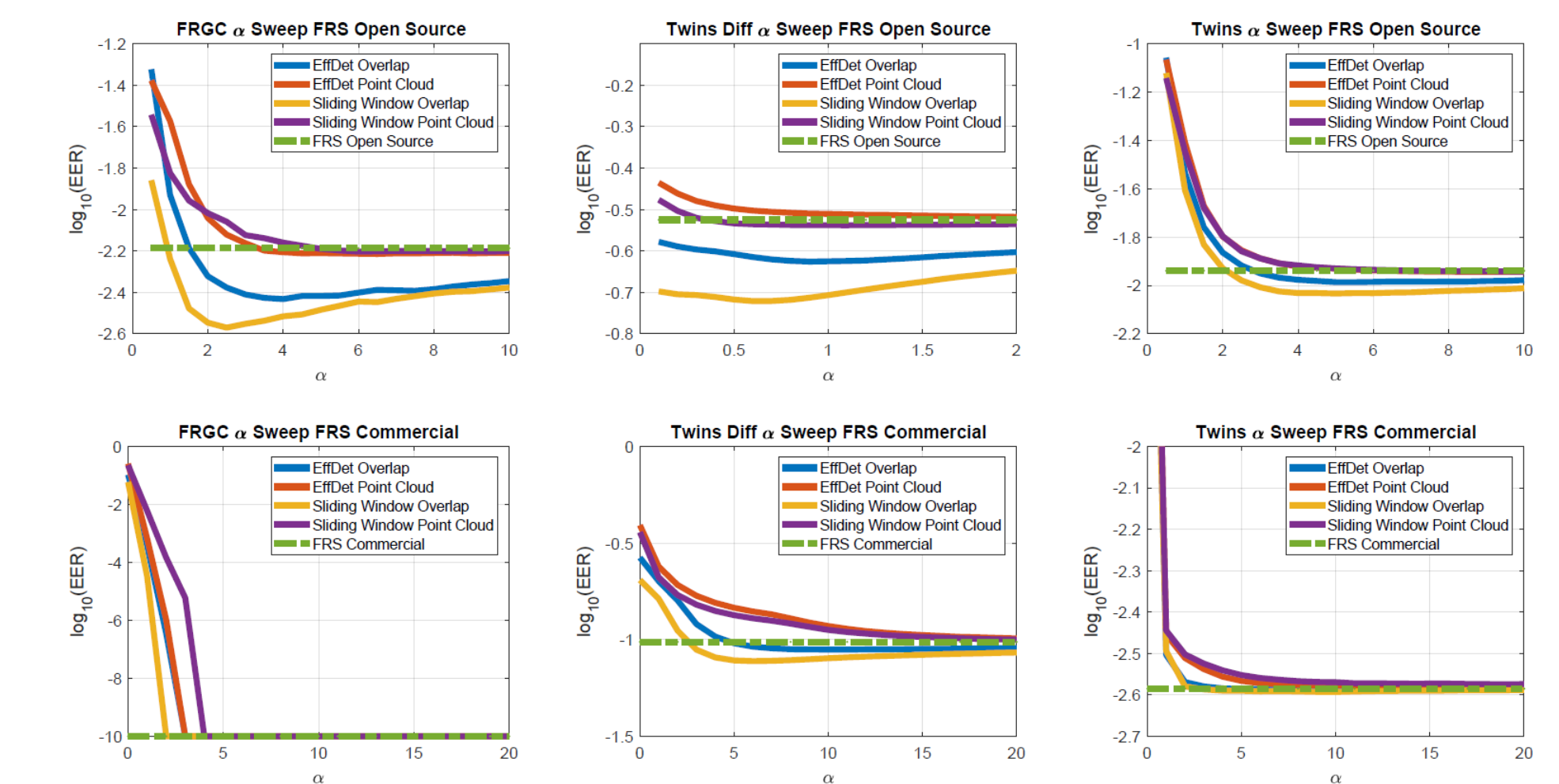
## Results

- RQ1: FMR using modern CNN architectures attains state-of-the-art accuracy, larger patch size and transfer learning can have positive effect, using off-center facial mark patches has a negative effect.
- RQ2: Comparable results, timing  $0.51 \pm 0.25 \mu s$  (Sliding window) versus  $0.046 \pm 0.072 \mu s$  (EfficientDet).
- RQ3: Hierarchical sliding window technique outperforms every corresponding EfficientDet implementation,  $s_o$  is significantly better than  $s_{pc}$ , clear difference between open source and commercial FRS, in Twin Diff case two facial mark location based systems perform better than open source FRS.



## Results

- RQ4: Open source FRS benefits from up to 59% EER reduction, commercial FRS achieves 20% reduction of the EER.



## Conclusion

- FMR: deep learning detection models outperform custom models, patch size positive, off-center negative, transfer learning positive influence on EER.
- FMD works well visually, differences in db's and methods.
- Sliding window/overlap score best combination for FM based FRS.
- Fusion FRS: open source FRS (up to 59%)/commercial FRS (up to 20%) EER reduction, increases explainability of the fused results.

## References

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